



Wavelet-Based Filter for Noise and Background Removal in Extended Depth of Field Microscopy Sneha Sharma^{1,2}, Qilin Deng², Prof. Lei Tian² Eastlake High School, 400 228th Ave NE, Sammamish, WA 98074¹ Department of Electrical and Computer Engineering, Boston University, 8 St. Mary's Street, Boston, MA 02215²

INTRODUCTION

- Miniaturized microscopes (miniscopes) have a limited **depth of field** \rightarrow the Tian Lab is developing an extended depth-of-field (EDoF) miniscope using deep learning and optics to view deeper into the brain¹
- **Issue:** Images taken with miniscopes contain slow-varying background, due to fluorescence from out-of-focus planes and scattered light. High frequency noise is also introduced by the detection system.
- Wavelet Filter: Applies wavelets (small wave-like oscillations localized in time) as a high- and low-pass filters to separate and extract the low-frequency and **high-frequency components** of an image² **Objective:** Implement a wavelet filter in our end-to-end EDoF pipeline's preprocessing steps to remove out-of-focus noise and background from our data

METHODOLOGY



- **Physical model's weights were frozen** \rightarrow pre-trained weights were imported and **model trained on weights in** the reconstruction network
- Trained for 60,000 epochs and utilized three loss metrics:
 - 1) 1) Mean-squared error (MSE): ensure similarity between target and output
 - Gradient-based loss (GradLoss): ensure similar 2) edges to retain neuron shapes
 - Fourier mean average error (fMAE): ensure similarity 3) between Fourier domain of target and output

RESULTS

Model Metrics

- Code Environment: Visual Studio Code
- Implementation: Python Pytorch Pytorch-Wavelets³
- **GPU**: NVIDIA A100/A4/L40S (depending on run)
- Loss: MSE + GradLoss + fMAE

Wavelet Type: Sometimes, images were processed best with the db1 wavelet (shown) below). Other times, images were processed best with the db2 wavelet.

Output vs. Target

Ground Truth

PSNR:

20.96

SSIM:

74.15

MSE:

0.080

- Wavelet Basis: db1 and db2
- Full-Width of Half-Maximum (FWHM) of PSF: 8.0
- **Noise Level**: 2.0
- Runtime With No Preprocessing Layer: 5hr 40min
- **Runtime With Wavelet Filter***: 5hr 52min

*Calculated by averaging 6 runs with different hyperparameters (learning rate, scheduler, wavelet type, etc.)

Unprocessed

Processed w/ db1 (Wavelet Shown in Corner)

Processed w/ db2 (Wavelet Shown in Corner)

Learning Rate Scheduler: The Cyclic Learning Rate Scheduler (causing the learning rate to cycle between 5e-9 and 5e-7 every 2000 epochs) performed the best across all loss metrics, achieving a total loss of 0.9809.

- Hyperparameter tuning shows that setting the FWHM of the PSF and the noise level as fixed values based on the optical system yields best results following the preprocessing layer
- The wavelet filter ensured that the model could converge fast and accurately by getting rid of the out-of-focus fluorescence background and noise, thereby encouraging it to focus training on the most important parts of the data with **little significant increase in computational time**
- Model performed best when wavelet filter outputted a stack of the unprocessed image processed with the db1 wavelet, and the image processed with the db2 wavelet
- Future Directions:
 - Test Wavelet Filter with different combinations of wavelets to find the most optimal one: run more tests with the Symlet family because of its small support and use in denoising images
 - Improve loss metrics: focus on **decreasing loss within the Fourier domain**

REFERENCES

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